TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOSIII)

TPCS8204

Lithium Ion Battery Applications Notebook PC Applications Portable Equipment Applications

- Small footprint due to small and thin package
- Low drain-source ON resistance: $RDS(ON) = 13 \text{ m}\Omega \text{ (typ.)}$
- High forward transfer admittance: $|Y_{fs}| = 15 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = 10 \mu A \text{ (max) (V}_{DS} = 20 \text{ V)}$
- Enhancement-mode: $V_{th} = 0.5 \sim 1.2 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 200 \text{ }\mu\text{A})$

Maximum Ratings (Ta = 25°C)

Char	acteristics	Symbol	Rating	Unit	
Drain-source vol	tage	V _{DSS}	20	V	
Drain-gate voltag	ge (R _{GS} = 20 kΩ)	V_{DGR}	20	V	
Gate-source volt	age	V _{GSS}	±12	V	
Drain current	DC (Note 1)	I _D	6	Α	
Dialii cuitetti	Pulse (Note 1)	VDSS 20 VDGR 20 VGSS ±12 Dte 1) ID 6 Dte 1) IDP 24 e 3a) PD (1) 1.1 alue n e 3b) PD (2) 0.75 e 3a) PD (1) 0.6 alue n e 3b) PD (2) 0.35 e 3b) Dte 4) EAS 46.8 tion	A		
Drain power dissipation	Single-device operation (Note 3a)	P _{D (1)}	1.1		
(t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	P _{D (2)}	0.75	W	
Drain power dissipation (t = 10 s) (Note 2b)	Single-device operation (Note 3a)	P _{D (1)}	0.6		
	Single-device value at dual operation (Note 3b)	P _{D (2)}	0.35	W	
Single pulse avalanche energy (Note 4)		E _{AS}	46.8	mJ	
Avalanche currer	nt	I _{AR}	6	Α	
Repetitive avalar Single-device va	nche energy lue at dual operation (Note 2a, 3b, 5)	E _{AR}	0.075	mJ	
Channel tempera	ature	T _{ch}	150	°C	
Storage tempera	ture range	T _{stg}	-55~150	°C	

Unit: mm

(0.525)

1. DRAIN
2. 3. SOURCE
4. GATE
8. DRAIN

JEDEC

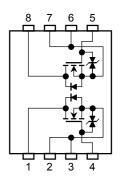
JEITA

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2-3R1E

Weight: 0.035 g (typ.)

Circuit Configuration



Note: For (Note 1), (Note 2), (Note 3), (Note 4) and (Note 5), please refer to the next page.

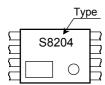
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This transistor is an electrostatic sensitive device. Please handle with caution.

Thermal Characteristics

Characteristics	Symbol	Max	Unit		
The small registered showned to embient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	114	°C/W	
Thermal resistance, channel to ambient (t = 10 s) (Note 2a)	Single-device value at dual operation (Note 3b)	R _{th} (ch-a) (2)	167		
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	208		
(t = 10 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	357	°C/W	

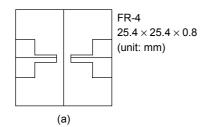
Marking (Note 6)



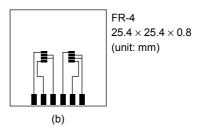
Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2:

a) Device mounted on a glass-epoxy board (a)



b) Device mounted on a glass-epoxy board (b)



Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device. (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device. (During dual operation, power is evenly applied to both devices.)

Note 4:
$$V_{DD} = 16 \text{ V}$$
, $T_{ch} = 25^{\circ}\text{C}$ (initial), $L = 1.0 \text{ mH}$, $R_G = 25 \Omega$, $I_{AR} = 6 \text{ A}$

Note 5: Repetitive rating; pulse width limited by maximum channel temperature

* shows lot number. (year of manufacture: last decimal digit of the year of manufacture, month of manufacture: January to December are denoted by letters A to L respectively.)

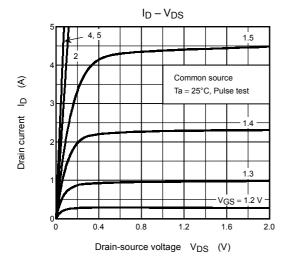
Electrical Characteristics (Ta = 25°C)

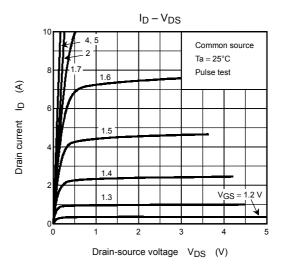
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cui	Sate leakage current		$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain cut-OFF cu	ırrent	I _{DSS}	V _{DS} = 20 V, V _{GS} = 0 V	10		10	μΑ
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	20	_	_	V
Diam-source bre	ardown voltage	V _{(BR)DSX}	$I_D = 10 \text{ mA}, V_{GS} = -12 \text{ V}$	8 — —		·	
Gate threshold v	oltage	V _{th}	$V_{DS} = 10 \text{ V}, I_D = 200 \mu\text{A}$	0.5	_	1.2	V
Drain-source ON resistance			$V_{GS} = 2.0 \text{ V}, I_D = 4.2 \text{ A}$	_	24	35	mΩ
		R _{DS (ON)}	V _{GS} = 2.5 V, I _D = 4.2 A	_	18	22	
			V _{GS} = 4.0 V, I _D = 4.8 A	_	13	17	
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 3.0 A	7.5	15	_	S
Input capacitance		C _{iss}		_	2160	_	
Reverse transfer	capacitance	C _{rss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	210	_	pF
Output capacitance		C _{oss}		_	230	_	
Switching time	Rise time	t _r	VGS 2 V	_	5	_	- ns
	Turn-ON time	t _{on}		_	13	_	
	Fall time	t _f		_	10	_	
	Turn-OFF time	t _{off}	$V_{DD} \simeq 10 \text{ V}$ Duty \leq 1%, $t_W = 10 \mu\text{s}$	_	53	_	
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \approx 16 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 6 \text{ A}$	_	22	_	
Gate-source charge 1		Q _{gs1}		_	4	_	nC
Gate-drain ("miller") charge		Q _{gd}		_	5	_	

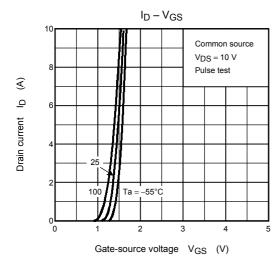
Source-Drain Ratings and Characteristics (Ta = 25°C)

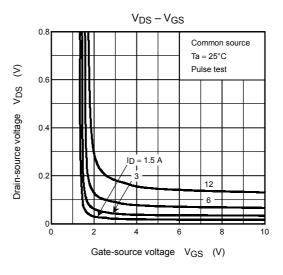
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	_	_	_	24	Α
Forward voltage (diode)		V_{DSF}	$I_{DR} = 6 \text{ A}, V_{GS} = 0 \text{ V}$	_	_	-1.2	V

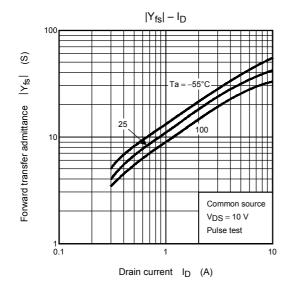
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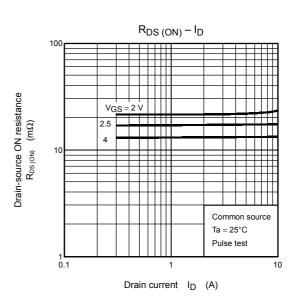


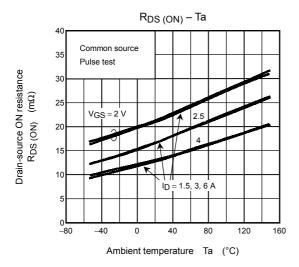


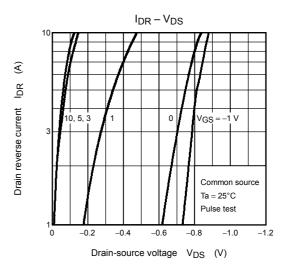


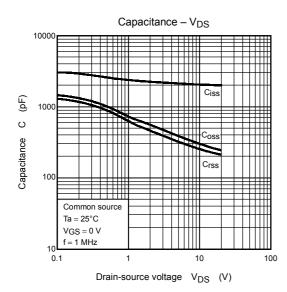


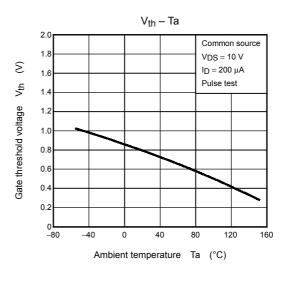


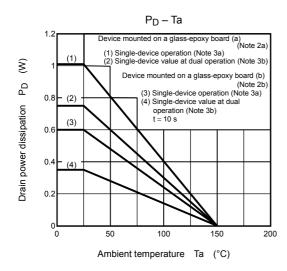


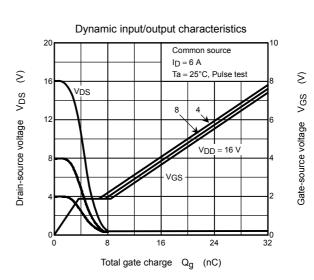




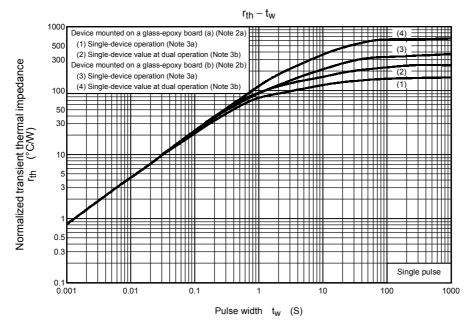




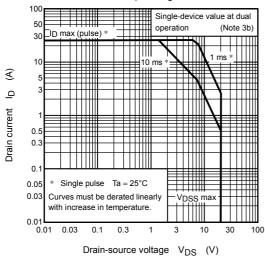




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